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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	I <sup>2</sup> C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	13
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	16-SOIC (0.154", 3.90mm Width)
Supplier Device Package	16-SOIC
Purchase URL	<a href="https://www.e-xfl.com/product-detail/silicon-labs/efm8bb10f8g-a-soic16r">https://www.e-xfl.com/product-detail/silicon-labs/efm8bb10f8g-a-soic16r</a>

## 2. Ordering Information

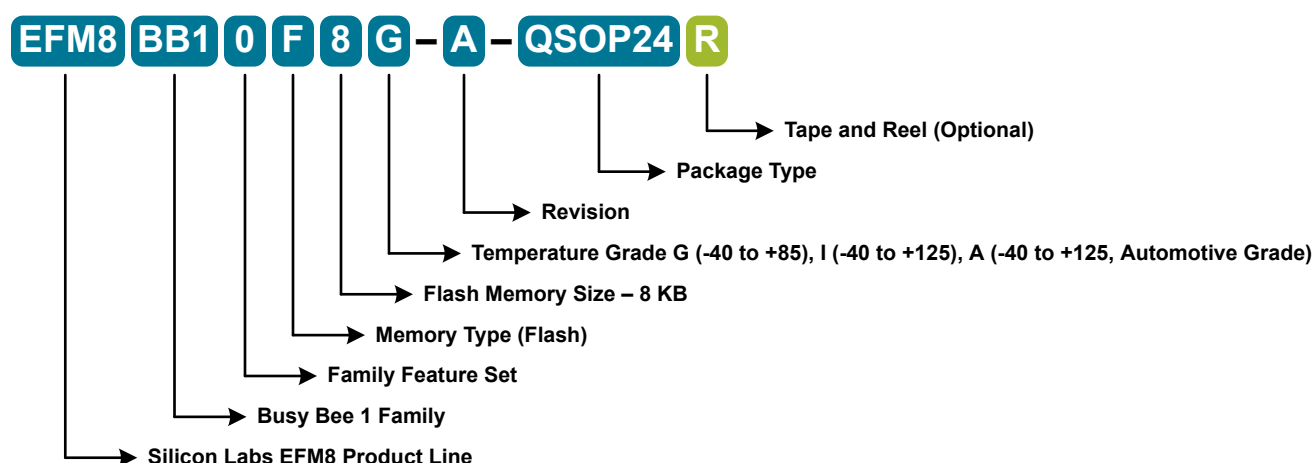


Figure 2.1. EFM8BB1 Part Numbering

All EFM8BB1 family members have the following features:

- CIP-51 Core running up to 25 MHz
- Two Internal Oscillators (24.5 MHz and 80 kHz)
- SMBus / I2C
- SPI
- UART
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 4 16-bit Timers
- 2 Analog Comparators
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit
- AEC-Q100 qualified
- Pre-loaded UART bootloader

In addition to these features, each part number in the EFM8BB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8BB10F8G-A-QSOP24	8	512	18	16	8	8	Yes	-40 to +85 C	QSOP24
EFM8BB10F8G-A-QFN20	8	512	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F8G-A-SOIC16	8	512	13	12	6	6	Yes	-40 to +85 C	SOIC16
EFM8BB10F4G-A-QFN20	4	512	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F2G-A-QFN20	2	256	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F8I-A-QSOP24	8	512	18	16	8	8	Yes	-40 to +125 C	QSOP24

## 3. System Overview

### 3.1 Introduction

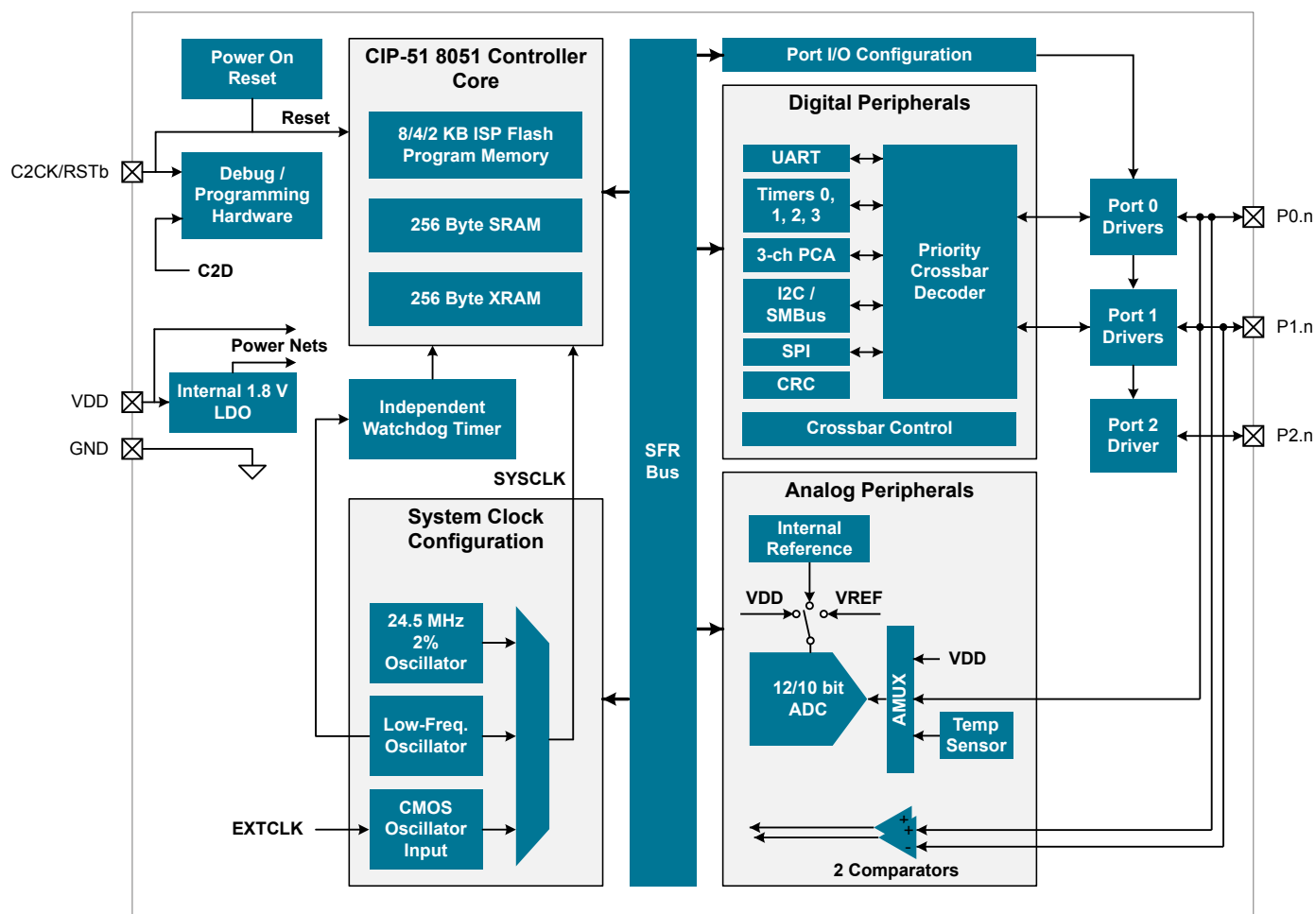


Figure 3.1. Detailed EFM8BB1 Block Diagram

This section describes the EFM8BB1 family at a high level. For more information on each module including register definitions, see the EFM8BB1 Reference Manual.

### 3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

**Table 3.1. Power Modes**

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	—	—
Idle	<ul style="list-style-type: none"> <li>Core halted</li> <li>All peripherals clocked and fully operational</li> <li>Code resumes execution on wake event</li> </ul>	Set IDLE bit in PCON0	Any interrupt
Stop	<ul style="list-style-type: none"> <li>All internal power nets shut down</li> <li>Pins retain state</li> <li>Exit on any reset source</li> </ul>	<ol style="list-style-type: none"> <li>1. Clear STOPCF bit in REG0CN</li> <li>2. Set STOP bit in PCON0</li> </ol>	Any reset source
Shutdown	<ul style="list-style-type: none"> <li>All internal power nets shut down</li> <li>Pins retain state</li> <li>Exit on pin or power-on reset</li> </ul>	<ol style="list-style-type: none"> <li>1. Set STOPCF bit in REG0CN</li> <li>2. Set STOP bit in PCON0</li> </ol>	<ul style="list-style-type: none"> <li>RSTb pin reset</li> <li>Power-on reset</li> </ul>

### 3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P1.7 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pins P2.0 and P2.1 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P2.0.

- Up to 18 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- Up to 16 direct-pin interrupt sources with shared interrupt vector (Port Match).

### 3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 24.5 MHz oscillator divided by 8.

- Provides clock to core and peripherals.
- 24.5 MHz internal oscillator (HFOSC0), accurate to  $\pm 2\%$  over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0).
- External CMOS clock input (EXTCLK).
- Clock divider with eight settings for flexible clock scaling: Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.

## 3.7 Analog

### 12-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12-, 10-, and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 16 external inputs.
- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 200 ksps samples per second in 12-bit mode or 800 ksps samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal fast-settling reference with two levels (1.65 V and 2.4 V) and support for external reference and signal ground.
- Integrated temperature sensor.

### Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator module includes the following features:

- Up to 8 external positive inputs.
- Up to 8 external negative inputs.
- Additional input options:
  - Internal connection to LDO output.
  - Direct connection to GND.
- Synchronous and asynchronous outputs can be routed to pins via crossbar.
- Programmable hysteresis between 0 and  $\pm 20$  mV
- Programmable response time.
- Interrupts generated on rising, falling, or both edges.

### 3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset

### 3.9 Debugging

The EFM8BB1 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

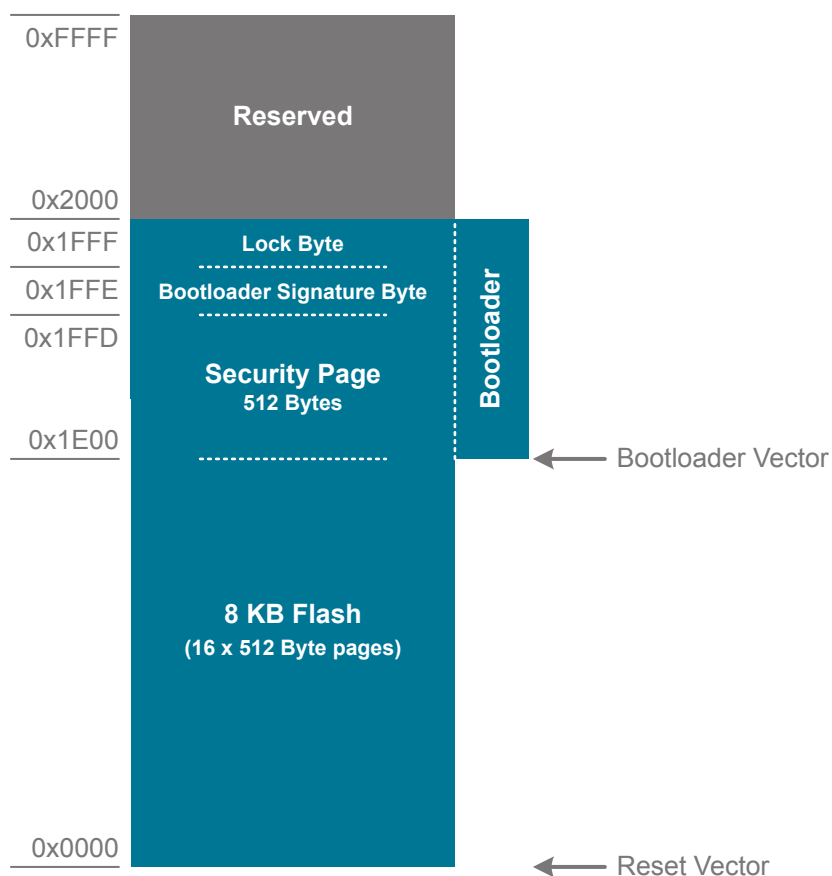
### 3.10 Bootloader

All devices come pre-programmed with a UART bootloader. This bootloader resides in the code security page, which is the last last page of code flash; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

More information about the bootloader protocol and usage can be found in *AN945: EFM8 Factory Bootloader User Guide*. Application notes can be found on the Silicon Labs website ([www.silabs.com/8bit-appnotes](http://www.silabs.com/8bit-appnotes)) or within Simplicity Studio by using the [Application Notes] tile.



**Figure 3.2. Flash Memory Map with Bootloader—8 KB Devices**

**Table 3.2. Summary of Pins for Bootloader Communication**

Bootloader	Pins for Bootload Communication
UART	TX – P0.4
	RX – P0.5

**Table 3.3. Summary of Pins for Bootload Mode Entry**

Device Package	Pin for Bootload Mode Entry
QSOP24	P2.0 / C2D
QFN20	P2.0 / C2D
SOIC16	P2.0 / C2D



#### 4.1.11 Comparators

Table 4.11. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	$t_{RESP0}$	+100 mV Differential	—	100	—	ns
		–100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Low- est Power)	$t_{RESP3}$	+100 mV Differential	—	1.5	—	μs
		–100 mV Differential	—	3.5	—	μs
Positive Hysteresis Mode 0 (CPMD = 00)	$HYS_{CP+}$	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	$HYS_{CP-}$	CPHYN = 00	—	–0.4	—	mV
		CPHYN = 01	—	–8	—	mV
		CPHYN = 10	—	–16	—	mV
		CPHYN = 11	—	–32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	$HYS_{CP+}$	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	$HYS_{CP-}$	CPHYN = 00	—	–0.5	—	mV
		CPHYN = 01	—	–6	—	mV
		CPHYN = 10	—	–12	—	mV
		CPHYN = 11	—	–24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	$HYS_{CP+}$	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	$HYS_{CP-}$	CPHYN = 00	—	–0.6	—	mV
		CPHYN = 01	—	–4.5	—	mV
		CPHYN = 10	—	–9	—	mV
		CPHYN = 11	—	–18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	$HYS_{CP+}$	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS <sub>CP-</sub>	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V <sub>IN</sub>		-0.25	—	V <sub>DD</sub> +0.25	V
Input Pin Capacitance	C <sub>CP</sub>		—	7.5	—	pF
Common-Mode Rejection Ratio	CMRR <sub>CP</sub>		—	70	—	dB
Power Supply Rejection Ratio	PSRR <sub>CP</sub>		—	72	—	dB
Input Offset Voltage	V <sub>OFF</sub>	T <sub>A</sub> = 25 °C	-10	0	10	mV
Input Offset Tempco	TC <sub>OFF</sub>		—	3.5	—	μV/°C

#### 4.1.13 SMBus

**Table 4.13. SMBus Peripheral Timing Performance (Master Mode)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Standard Mode (100 kHz Class)</b>						
I2C Operating Frequency	$f_{I2C}$		0	—	70 <sup>2</sup>	kHz
SMBus Operating Frequency	$f_{SMB}$		40 <sup>1</sup>	—	70 <sup>2</sup>	kHz
Bus Free Time Between STOP and START Conditions	$t_{BUF}$		9.4	—	—	μs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	μs
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	μs
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	μs
Data Hold Time	$t_{HD:DAT}$		489 <sup>3</sup>	—	—	ns
Data Setup Time	$t_{SU:DAT}$		448 <sup>3</sup>	—	—	ns
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	$t_{LOW}$		4.7	—	—	μs
Clock High Period	$t_{HIGH}$		9.4	—	50 <sup>4</sup>	μs
<b>Fast Mode (400 kHz Class)</b>						
I2C Operating Frequency	$f_{I2C}$		0	—	255 <sup>2</sup>	kHz
SMBus Operating Frequency	$f_{SMB}$		40 <sup>1</sup>	—	255 <sup>2</sup>	kHz
Bus Free Time Between STOP and START Conditions	$t_{BUF}$		2.6	—	—	μs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	μs
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	μs
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	μs
Data Hold Time	$t_{HD:DAT}$		489 <sup>3</sup>	—	—	ns
Data Setup Time	$t_{SU:DAT}$		448 <sup>3</sup>	—	—	ns
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	$t_{LOW}$		1.3	—	—	μs
Clock High Period	$t_{HIGH}$		2.6	—	50 <sup>4</sup>	μs

## 4.2 Thermal Conditions

**Table 4.15. Thermal Conditions**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance (Junction to Ambient)	$\theta_{JA}$	SOIC-16 Packages	—	70	—	°C/W
		QFN-20 Packages	—	60	—	°C/W
		QSOP-24 Packages	—	65	—	°C/W
Thermal Resistance (Junction to Case)	$\theta_{JC}$	QFN-20 Packages	—	28.86	—	°C/W

**Note:**

1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

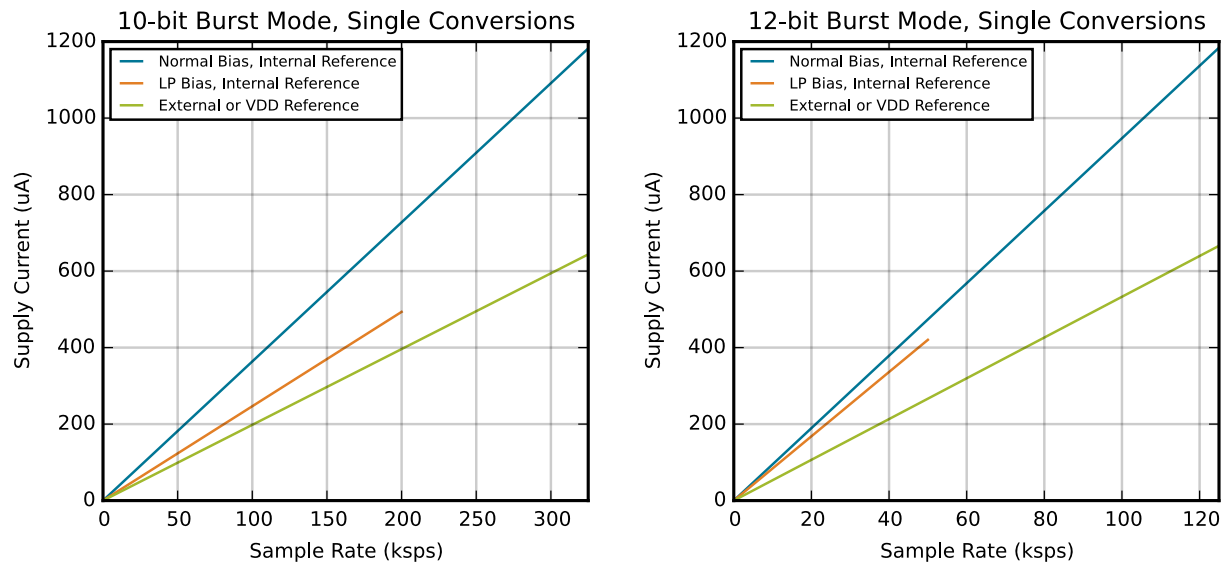
## 4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.16 Absolute Maximum Ratings on page 26](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

**Table 4.16. Absolute Maximum Ratings**

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	$T_{BIAS}$		–55	125	°C
Storage Temperature	$T_{STG}$		–65	150	°C
Voltage on VDD	$V_{DD}$		GND–0.3	4.2	V
Voltage on I/O pins or RST	$V_{IN}$	$V_{DD} \geq 3.3\text{ V}$	GND–0.3	5.8	V
		$V < 3.3\text{ V}$	GND–0.3	$V_{DD}+2.5$	V
Total Current Sunk into Supply Pin	$I_{VDD}$		—	200	mA DD
Total Current Sourced out of Ground Pin	$I_{GND}$		200	—	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	$I_{IO}$		–100	100	mA
Operating Junction Temperature	$T_J$	$T_A = -40\text{ °C to }85\text{ °C}$	–40	105	°C
		$T_A = -40\text{ °C to }125\text{ °C}$ (I-grade or A-grade parts only)	–40	130	°C

Exposure to maximum rating conditions for extended periods may affect device reliability.



**Figure 4.4. Typical ADC0 and Internal Reference Supply Current in Burst Mode**

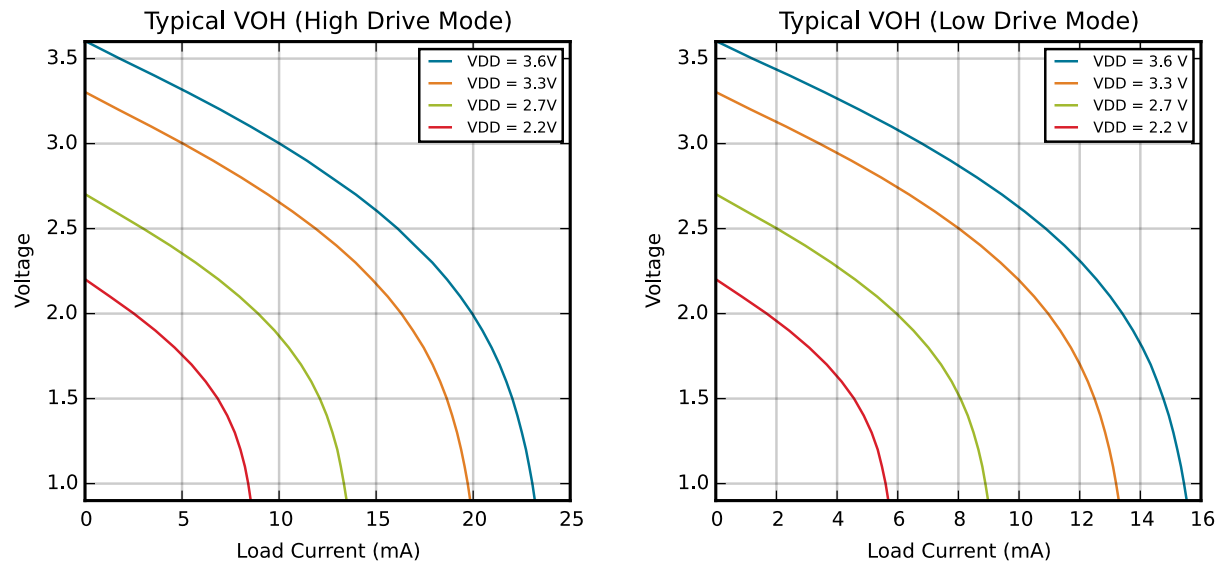


Figure 4.6. Typical  $V_{OH}$  Curves

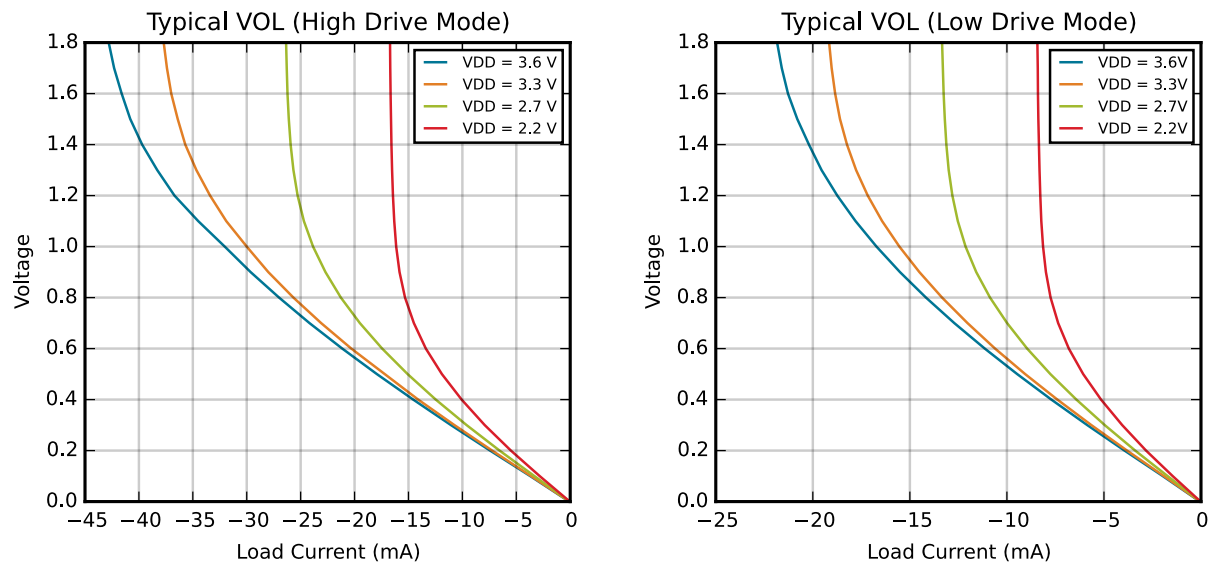


Figure 4.7. Typical  $V_{OL}$  Curves

## 6. Pin Definitions

### 6.1 EFM8BB1x-QSOP24 Pin Definitions

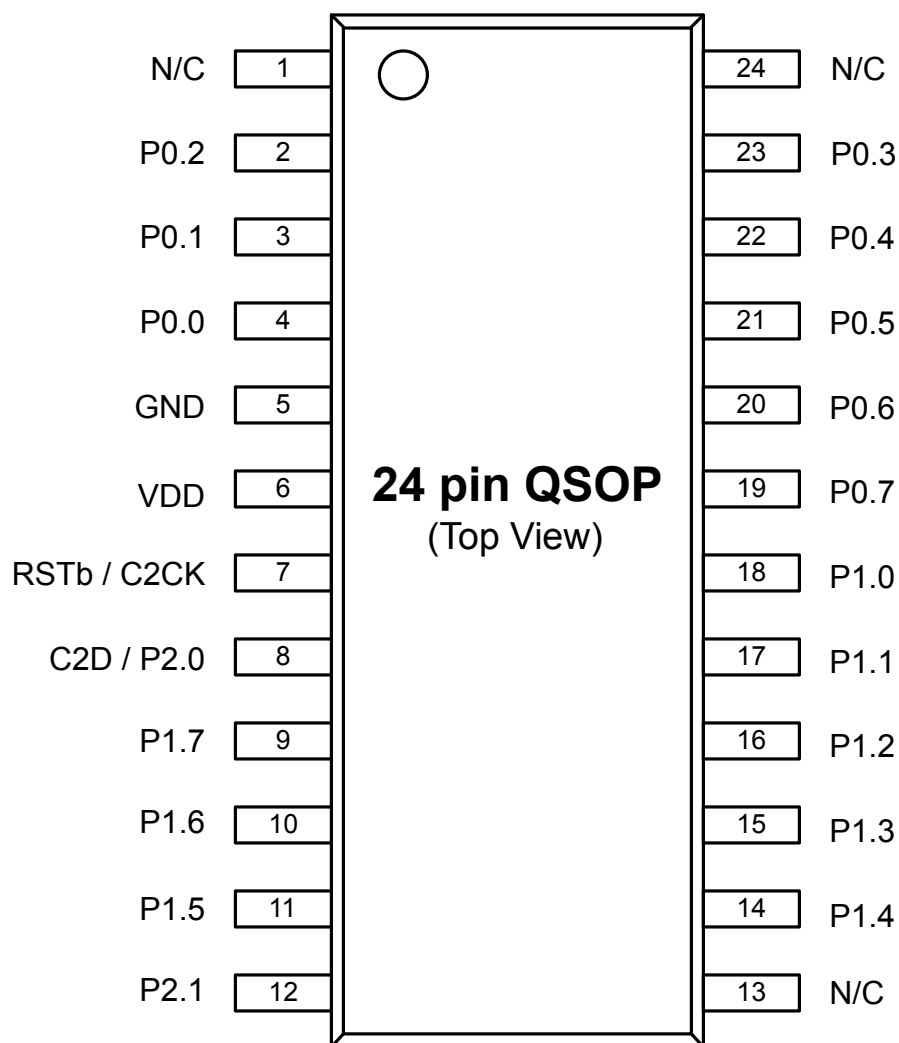


Figure 6.1. EFM8BB1x-QSOP24 Pinout

Table 6.1. Pin Definitions for EFM8BB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
17	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1
18	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0
19	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7
20	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.6 CMP0N.6
21	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0P.5 CMP0N.5
22	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.4 CMP0N.4
23	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 CMP0P.3 CMP0N.3
24	N/C	No Connection			



Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P2.0 / C2D	Multifunction I/O / C2 Debug Data			
7	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14 CMP1P.6 CMP1N.6
8	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP1P.5 CMP1N.5
9	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
10	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CMP1P.3 CMP1N.3
11	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CMP1P.2 CMP1N.2
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7
16	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.6 CMP0N.6

### 7.3 QSOP24 Package Marking



Figure 7.3. QSOP24 Package Marking

The package marking consists of:

- P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

## 8. QFN20 Package Specifications

### 8.1 QFN20 Package Dimensions

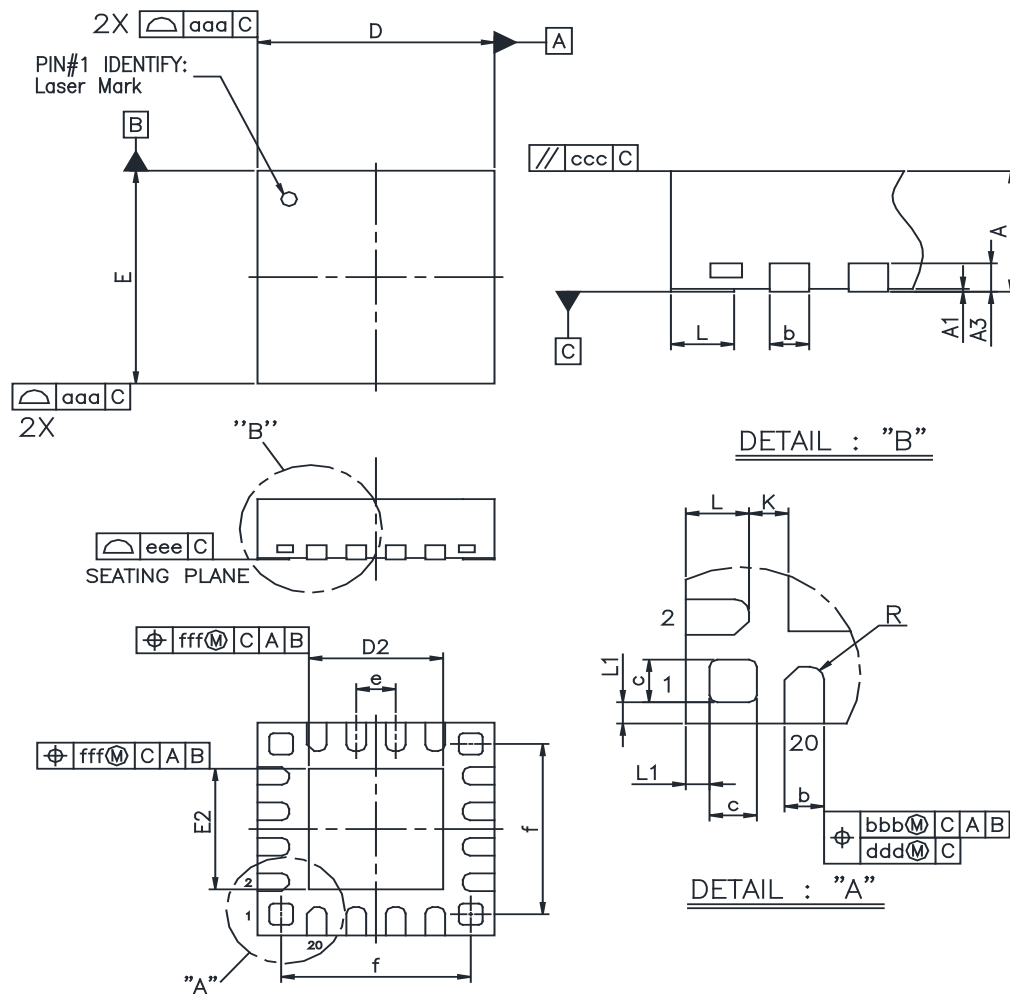


Figure 8.1. QFN20 Package Drawing

Table 8.1. QFN20 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3	0.20 REF		
b	0.18	0.25	0.30
c	0.25	0.30	0.35
D	3.00 BSC		
D2	1.6	1.70	1.80
e	0.50 BSC		

Dimension	Min	Typ	Max
h	0.25	—	0.50
θ	0°	—	8°
aaa	0.10		
bbb	0.20		
ccc	0.10		
ddd	0.25		

**Note:**

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to the JEDEC Solid State Outline MS-012, Variation AC.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

### 9.3 SOIC16 Package Marking



Figure 9.3. SOIC16 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).